



Patent No. NEC00P063-TOB

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**In re Application of:**

Kazuki Yokota

**Serial No.:** 09/627,456

**Group Art Unit:** 2851

**Filed:** July 27, 2000

**Examiner:** Magda Cruz

**For:** OVERLAY MARK, METHOD OF MEASURING OVERLAY ACCURACY,  
METHOD OF MAKING ALIGNMENT AND SEMICONDUCTOR DEVICE  
THEREWITH

Honorable Commissioner of Patents  
Alexandria, Virginia 22313-1450

**SUBMISSION OF VERIFIED ENGLISH TRANSLATION  
OF THE PRIORITY DOCUMENT**

Sir:

Submitted herewith is a copy of the verified English translation of the Specification, Claims and Abstract, and the Declaration of Tomoyuki Okazawa, dated January 26, 2004, that the English translation is a true English translation of the Japanese Application Number 1999-213720 filed July 28, 1999, upon which application the claim for priority is based.

Approval and acknowledgment of receipt are respectfully requested.

Respectfully submitted,

Fredric J. Zimmerman, Esq.  
Registration No. 48,747

Date:

1/29/04

McGinn & Gibb, PLLC  
Intellectual Property Law  
8321 Old Courthouse Road, Suite 200  
Vienna, VA 22182-3817  
(703) 761-4100  
Customer No. 21254